

Efficient focusing of 8 keV X-rays with multilayer Fresnel zone plates fabricated by atomic layer deposition and focused ion beam milling. Erratum

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Corrections to the article by Mayer *et al.* [*J. Synchrotron Rad.* (2013), **20**, 433–440] are given.

In the paper by Mayer *et al.* (2013), the two following errors are corrected:

On page 434, first column, line 17, it should read: ‘...and sub-10 nm (Ruhlandt *et al.*, 2012) using single MLLs’.

On page 437, second column, line 16, the effect of ‘apodization’ on the position of the first minimum of the Airy disk was erroneous. It should read: ‘... , to approximately 29.88 nm instead of 42.7 nm’. The error comes from a typo in the equation utilized to calculate this effect.

The authors apologize for these mistakes and for any inconvenience they might have caused.

References

- Mayer, M., Keskinbora, K., Grévent, C., Szeghalmi, A., Knez, M., Weigand, M., Snigirev, A., Snigireva, I. & Schütz, G. (2013). *J. Synchrotron Rad.* **20**, 433–440.
- Ruhlandt, A., Liese, T., Radisch, V., Kruger, S. P., Osterhoff, M., Giewekemeyer, K., Krebs, H. U. & Salditt, T. (2012). *AIP Adv.* **2**, 012175.